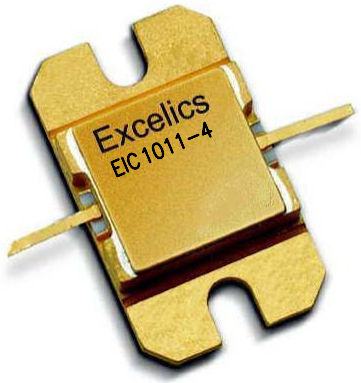
EIC1011-4

UPDATED 08/21/2007

10.70-11.70GHz 4-Watt Internally-Matched Power FET

FEATURES

- **10.70 –11.70GHz Bandwidth**
- **Input/Output Impedance Matched to 50 Ohms**
- **+36.0 dBm Output Power at 1dB Compression**
- **6.5 dB Power Gain at 1dB Compression**
- **30% Power Added Efficiency**
- **-46 dBc IM3 at Po = 25.5 dBm SCL**
- **100% Tested for DC, RF, and R_{TH}**



ELECTRICAL CHARACTERISTICS (T_a = 25°C)

Caution! ESD sensitive device.

SYMBOL	PARAMETERS/TEST CONDITIONS[1]	MIN	TYP	MAX	UNITS
P_{1dB}	Output Power at 1dB Compression f = 10.7-11.7GHz V_{DS} = 10 V, I_{DSQ} ≈ 1100mA	35.5	36.0		dBm
G_{1dB}	Gain at 1dB Compression f = 10.7-11.7GHz V_{DS} = 10 V, I_{DSQ} ≈ 1100mA	5.5	6.5		dB
ΔG	Gain Flatness f = 10.7-11.7GHz V_{DS} = 10 V, I_{DSQ} ≈ 1100mA			±0.6	dB
PAE	Power Added Efficiency at 1dB Compression V_{DS} = 10 V, I_{DSQ} ≈ 1100mA f = 10.7-11.7GHz		30		%
Id_{1dB}	Drain Current at 1dB Compression f = 10.7-11.7GHz		1100	1300	mA
IM3	Output 3rd Order Intermodulation Distortion Δf = 10 MHz 2-Tone Test; Pout = 25.5 dBm S.C.L[2] V_{DS} = 10 V, I_{DSQ} ≈ 65% IDSS f = 11.70GHz	-43	-46		dBc
I_{DSS}	Saturated Drain Current V_{DS} = 3 V, V_{GS} = 0 V		2000	2500	mA
V_P	Pinch-off Voltage V_{DS} = 3 V, I_{DS} = 20 mA		-2.5	-4.0	V
R_{TH}	Thermal Resistance[3]		5.5	6.0	°C/W

Note: 1. Tested with 100 Ohm gate resistor.
2. S.C.L. = Single Carrier Level.
3. Overall Rth depends on case mounting.

ABSOLUTE MAXIMUM RATING FOR EFE

SYMBOLS	PARAMETERS	ABSOLUTE[1]	CONTINUOUS[2]
Vds	Drain-Source Voltage	15V	10V
Vgs	Gate-Source Voltage	-5V	-4V
Igf	Forward Gate Current	48mA	14.4mA
Igr	Reverse Gate Current	-9.6mA	-2.4mA
Pin	Input Power	35.5dBm	@ 3dB Compression
Tch	Channel Temperature	175C	175C
Tstg	Storage Temperature	-65C to +175C	-65C to +175C
Pt	Total Power Dissipation	25W	25W

Note: 1. Exceeding any of the above ratings may result in permanent damage.
2. Exceeding any of the above ratings may reduce MTTF below design goals.

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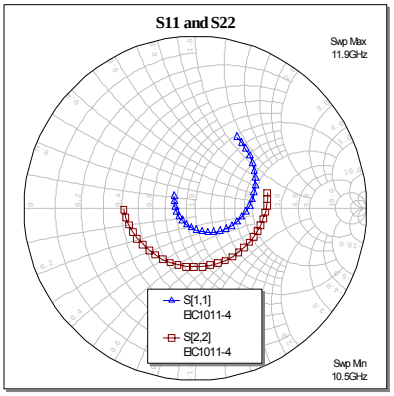
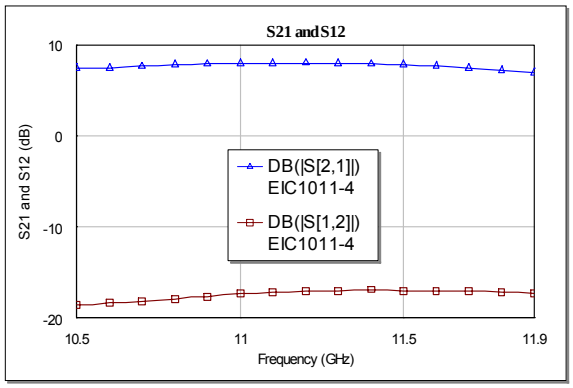
PERFORMANCE DATA

Typical S-Parameters (T= 25°C, 50Ω system, de-embedded to edge of package)
V_{DS} = 10 V, I_{DSQ} = 1100mA





FREQ	--- S11 ---		--- S21 ---		--- S12 ---		--- S22 ---	
(GHz)	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
10.0	0.5739	108.35	2.1901	-123.52	0.1038	-170.96	0.4584	55.24
10.2	0.5419	89.44	2.2517	-141.43	0.1081	171.77	0.4527	38.81
10.4	0.5027	69.8	2.3146	-159.96	0.1142	153.91	0.4397	21.79
10.6	0.454	49.43	2.3701	-178.6	0.1209	135.5	0.4186	2.16
10.8	0.3919	26.75	2.4477	162.08	0.1272	116.3	0.3848	-20.15
11.0	0.3168	2.48	2.5075	141.24	0.1368	95.69	0.359	-45.27
11.2	0.2355	-25.9	2.5133	119.63	0.1399	74.8	0.342	-75.08
11.4	0.1589	-62.62	2.4807	97.75	0.1436	52.35	0.3447	-107.19
11.6	0.1084	-118.22	2.4142	76.04	0.141	30.62	0.3633	-137.98
11.8	0.1171	176.36	2.2904	53.87	0.1378	9.3	0.4005	-166.15
12.0	0.1688	130.2	2.157	32.3	0.1337	-13.09	0.4409	169.07

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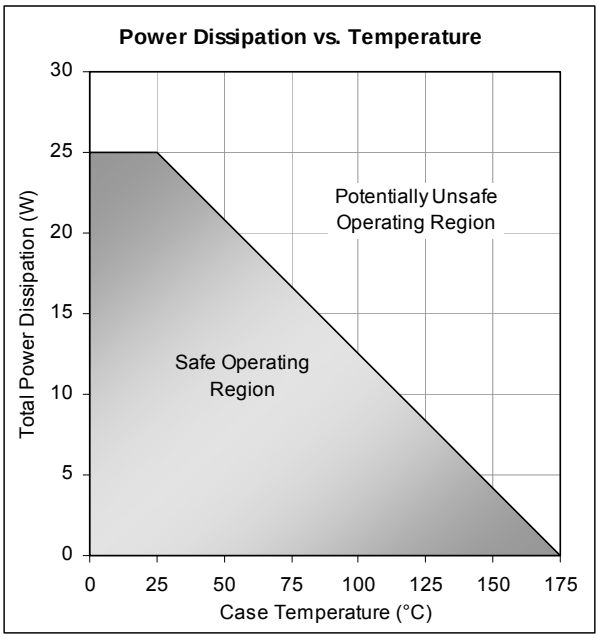
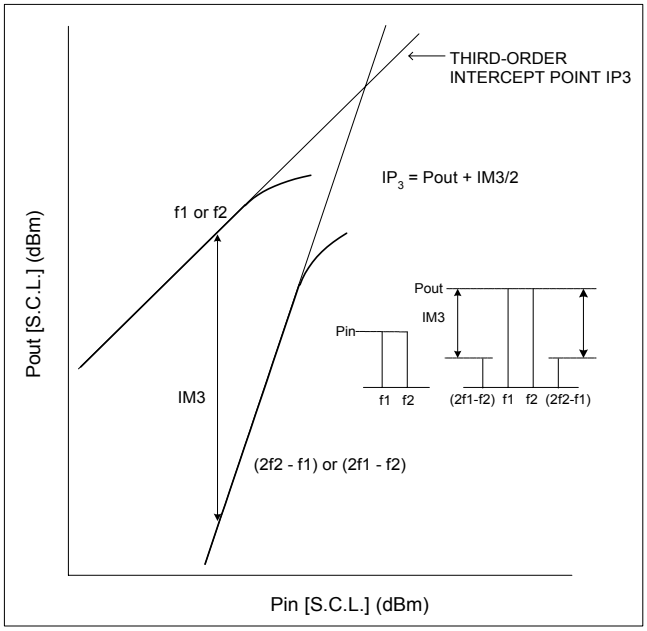
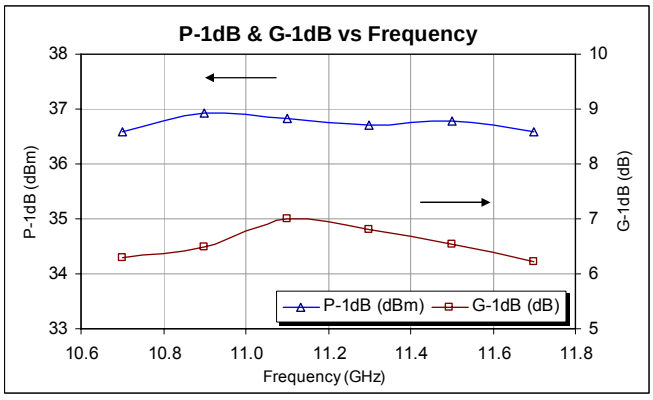
Power De-rating Curve and IM3 Definition

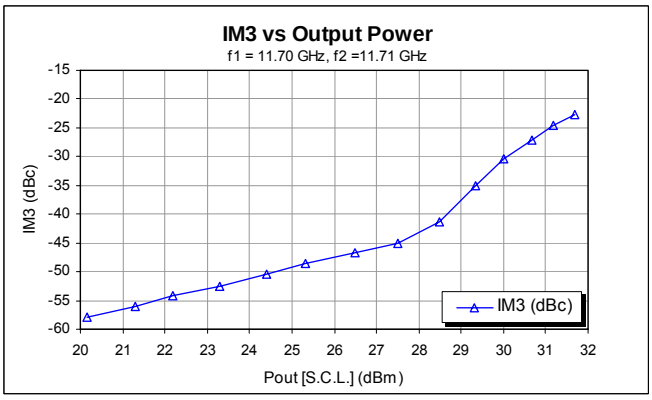




Typical Power Data (V_{DS} = 10 V, I_{DSQ} = 1100 mA)



Typical IM3 Data (V_{DS} = 10 V, I_{DSQ} ≈ 65% IDSS)



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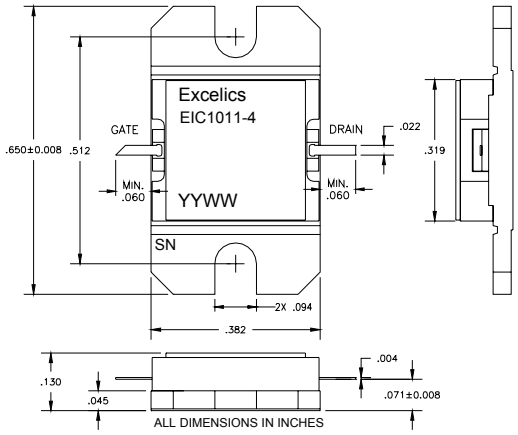
PACKAGES OUTLINE

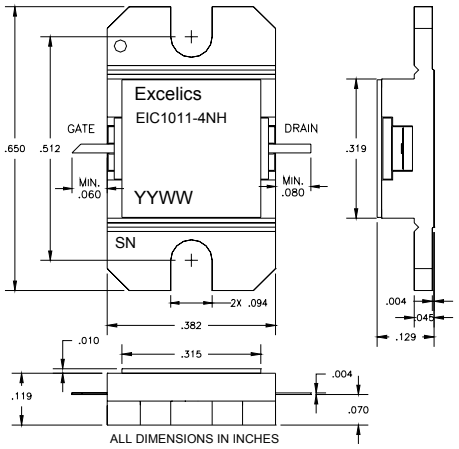
Dimensions in inches, Tolerance ± .005 unless otherwise specified

EIC1011-4 (Hermetic)



Caution! ESD sensitive device.

EIC1011-4NH (Non-Hermetic)



Caution! ESD sensitive device.

ORDERING INFORMATION

Part Number	Packages	Grade[1]	f_{Test} (GHz)	P_{1dB} (min)	IM_3 (min)[2]
EIC1011-4	Hermetic	Industrial	10.70-11.70GHz	35.5	-43
EIC1011-4NH	Non-Hermetic	Industrial	10.70-11.70GHz	35.5	-43

Notes: 1. Contact factory for military and hi-rel grades.
2. Exact test conditions are specified in "Electrical Characteristics" table.

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